

March 2015

# FDD6635

# 35V N-Channel PowerTrench® MOSFET

## **General Description**

This N-Channel MOSFET has been produced using Fairchild Semiconductor's proprietary PowerTrench technology to deliver low Rdson and optimized Bvdss capability to offer superior performance benefit in the applications.

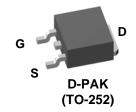
## **Applications**

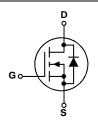
- Inverter
- Power Supplies

## **Features**

- 59 A, 35 V  $R_{DS(ON)} = 10 \ m\Omega \ @ \ V_{GS} = 10 \ V$   $R_{DS(ON)} = 13 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$
- · Fast Switching
- · RoHS compliant







Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage			35	V
V <sub>DS(Avalanche)</sub>	Drain-Source Avalanche Voltage (maximum) (Note 4)			40	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	V	
I <sub>D</sub>	Continuous Drain Current	@T <sub>C</sub> =25°C	(Note 3)	59	А
		@T <sub>A</sub> =25°C	(Note 1a)	15	
		Pulsed	(Note 1a)	100	
E <sub>AS</sub>	Single Pulse Avalanche E	nergy	(Note 5)	113	mJ
P <sub>D</sub>	Power Dissipation	@T <sub>c</sub> =25°C	(Note 3)	55	W
		@T <sub>A</sub> =25°C	(Note 1a)	3.8	
		@T <sub>A</sub> =25°C	(Note 1b)	1.6	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

## **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	2.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R <sub>e.IA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

**Package Marking and Ordering Information** 

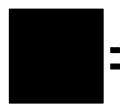
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Device Marking Device		Package	Reel Size Tape width		Quantity	
	FDD6635	FDD6635	D-PAK (TO-252)	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics(Note 2)			<u> </u>	<u> </u>	l .
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250  \mu\text{A}$	35			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$ , Referenced to 25°C		32		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 28 \text{ V},  V_{GS} = 0 \text{ V}$			1	μА
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		<b>-</b> 5		mV/°(
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$ \begin{vmatrix} V_{GS} = 10 \text{ V}, & I_D = 15 \text{ A} \\ V_{GS} = 4.5 \text{ V}, & I_D = 13 \text{ A} \\ V_{GS} = 10 \text{ V}, & I_D = 15 \text{ A}, T_J = 125 ^{\circ}\text{C} \\ \end{vmatrix} $		8.2 10.2 12.4	10 13 16	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 15 \text{ A}$		53		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance			1400		pF
Coss	Output Capacitance	$V_{DS} = 20 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		317		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1.0 MHz		137		pF
$R_{G}$	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.4		Ω
Switchin	q Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time			11	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 20 \text{ V}, \qquad I_D = 1 \text{ A},$		6	12	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		28	45	ns
t <sub>f</sub>	Turn-Off Fall Time	]		14	25	ns
Q <sub>g (TOT)</sub>	Total Gate Charge, V <sub>GS</sub> = 10V			26	36	nC
Qg	Total Gate Charge, V <sub>GS</sub> = 5V	$V_{DS} = 20 \text{ V}, I_{D} = 15 \text{ A}$		13	18	nC
$Q_{gs}$	Gate-Source Charge			3.9		nC
$Q_{gd}$	Gate-Drain Charge	]		5.3		nC

Electric	ai Characteristics	T <sub>A</sub> = 25°C unless otherwise noted					
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Drain-Sc	ource Diode Characteristics						
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_{S} = 15 \text{ A}$ (Note 2)		0.8	1.2	V	
trr	Diode Reverse Recovery Time	IF = 15 A, diF/dt = 100 A/μs		26		ns	
Qrr	Diode Reverse Recovery Charge			16		nC	

#### Notes

 R<sub>0,1A</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0,1C</sub> is guaranteed by design while R<sub>0,CA</sub> is determined by the user's board design.



a)  $R_{\theta JA} = 40$  °C/W when mounted on a  $1 \text{in}^2$  pad of 2 oz copper



b) R<sub>θJA</sub> = 96°C/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%

3. Maximum current is calculated as:  $\sqrt{\frac{P_D}{R_{DS(ON)}}}$ 

where  $P_D$  is maximum power dissipation at  $T_C = 25^{\circ}C$  and  $R_{DS(on)}$  is at  $T_{J(max)}$  and  $V_{GS} = 10V$ . Package current limitation is 21A

4. BV(avalanche) Single-Pulse rating is guaranteed if device is operated within the UIS SOA boundary of the device.

5. Starting  $T_J=25\,^{\circ}C,\,L=1mH,\,I_{AS}=15A,\,V_{DD}=35V,\,V_{GS}=10V$ 

# **Typical Characteristics**

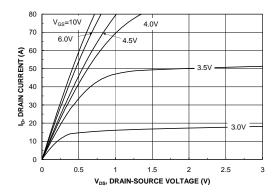


Figure 1. On-Region Characteristics

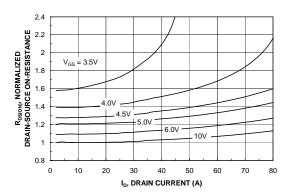


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

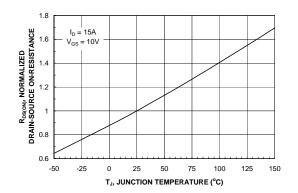


Figure 3. On-Resistance Variation with Temperature

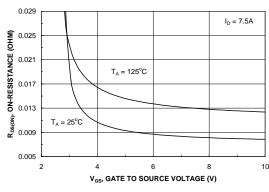


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

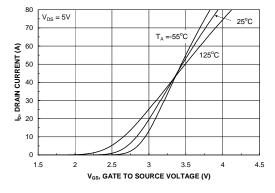


Figure 5. Transfer Characteristics

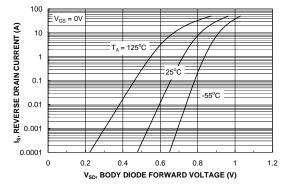


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

# **Typical Characteristics**

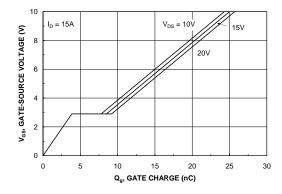


Figure 7. Gate Charge Characteristics

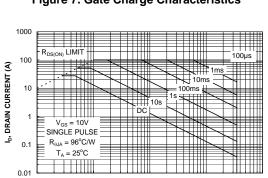


Figure 9. Maximum Safe Operating Area

 ${\rm V_{DS}},$  DRAIN-SOURCE VOLTAGE (V)

0.1

0.01

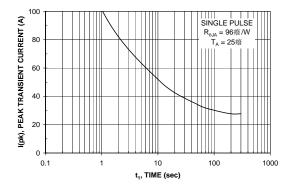


Figure 11. Single Pulse Maximum Peak Current

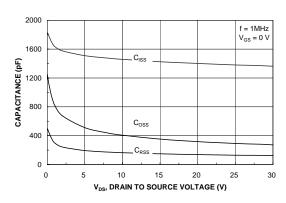


Figure 8. Capacitance Characteristics

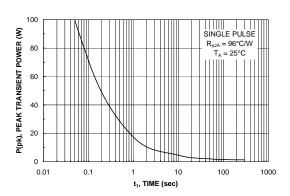


Figure 10. Single Pulse Maximum **Power Dissipation** 

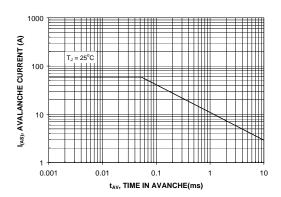


Figure 12. Unclamped Inductive Switching Capability

# **Typical Characteristics**

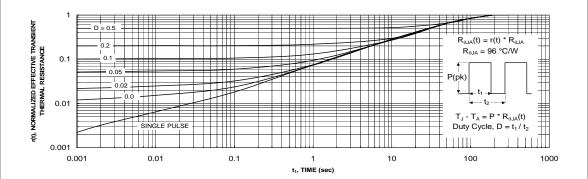
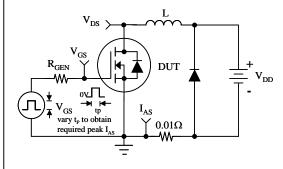


Figure 13. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

## **Test Circuits and Waveforms**



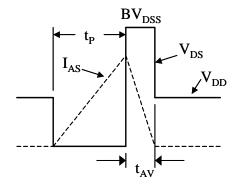
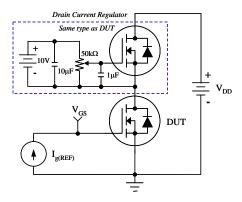


Figure 14. Unclamped Inductive Load Test Circuit

Figure 15. Unclamped Inductive Waveforms



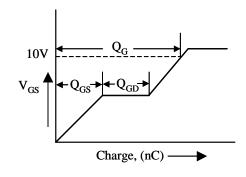
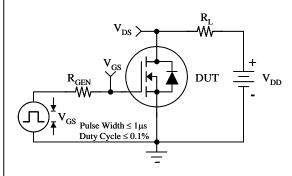


Figure 16. Gate Charge Test Circuit

Figure 17. Gate Charge Waveform



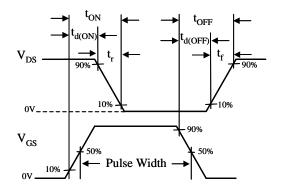
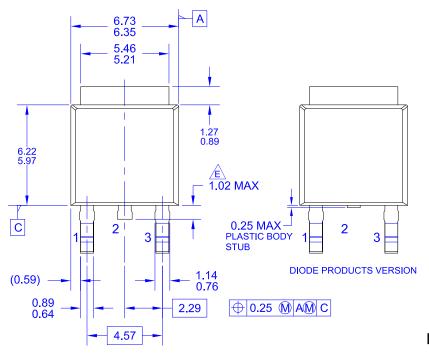
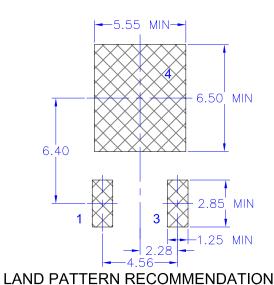


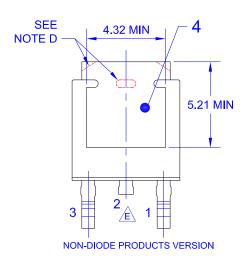
Figure 18. Switching Time Test Circuit

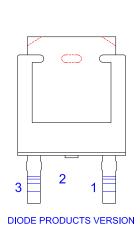
Figure 19. Switching Time Waveforms

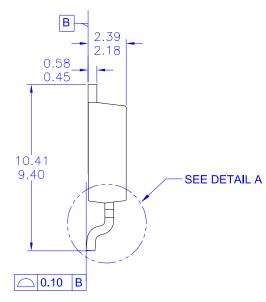




NON-DIODE PRODUCTS VERSION



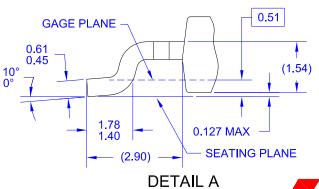




NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE CONFORMS TO JEDEC, TO-252,
- ISSUE C, VARIATION AA.

  B) ALL DIMENSIONS ARE IN MILLIMETERS.
  C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
- D) SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED CORNERS OR EDGE PROTRUSION.
- E) TRIMMED CENTER LEAD IS PRESENT ONLY FOR DIODE PRODUCTS
- F) DIMENSIONS ARE EXCLUSSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS.
- G) LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD TO228P991X239-3N.
- H) DRAWING NUMBER AND REVISION: MKT-TO252A03REV10



(ROTATED -90°) SCALE: 12X







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Definition of Terms						
Datasheet Identification		Definition				
Advance Information Formative / In Design		Datasheet contains the design specifications for product development. Specifications may chang in any manner without notice.				
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No Identification Needed Full Production		Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.				
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Rev. 174